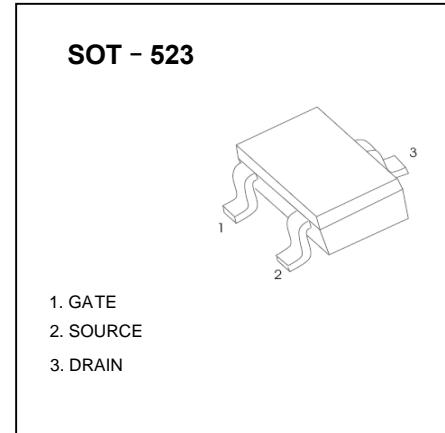
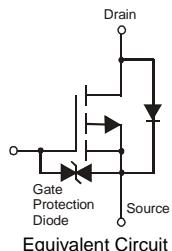


Plastic-Encapsulate MOSFETS

P-CHANNEL ENHANCEMENT MODE MOSFET

Features

- Low On-Resistance
- Low Gate Threshold Voltage
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Lead Free By Design/RoHS Compliant (Note 2)
- ESD Protected Up To 3kV



Marking Code: PA1

Maximum Ratings @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic		Symbol	Value	Units
Drain-Source Voltage		V_{DSS}	-20	V
Gate-Source Voltage		V_{GSS}	± 6	V
Drain Current (Note 1)	Steady State	I_D	-0.46 -0.33	A
Pulsed Drain Current		I_{DM}	-6	A

Thermal Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise specified

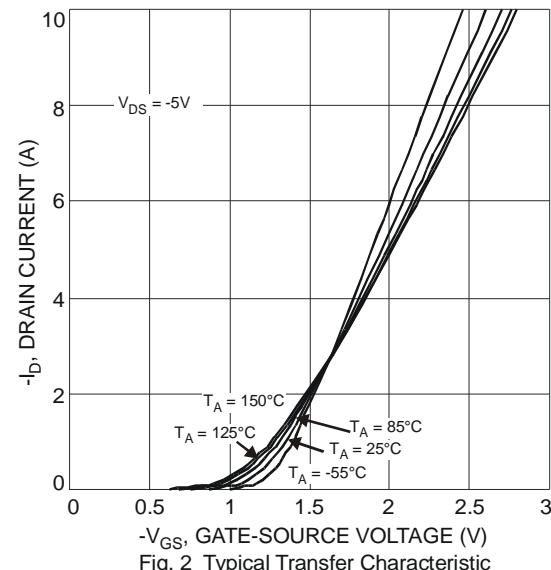
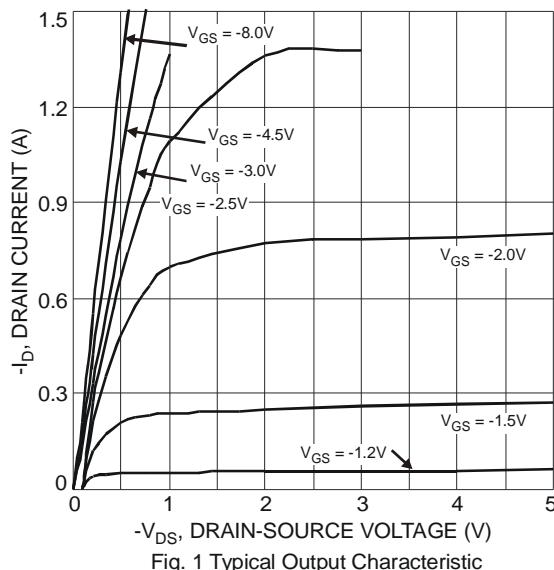
Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 1)	P_D	0.27	W
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	461	°C/W
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	°C

Notes: 1. Device mounted on FR-4 PCB.
2. No purposefully added lead.

Electrical Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 4)						
Drain-Source Breakdown Voltage	BV_{DSS}	-20	-	-	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = -250\mu\text{A}$
Zero Gate Voltage Drain Current $T_J = 25^\circ\text{C}$	I_{DSS}	-	-	-100	nA	$\text{V}_{\text{DS}} = -20\text{V}, \text{V}_{\text{GS}} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	-	-	± 2.0	μA	$\text{V}_{\text{GS}} = \pm 4.5\text{V}, \text{V}_{\text{DS}} = 0\text{V}$
ON CHARACTERISTICS (Note 4)						
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	-0.5	-	-1.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_D = -250\mu\text{A}$
Static Drain-Source On-Resistance	$\text{R}_{\text{DS}(\text{ON})}$	-	0.5	0.95	Ω	$\text{V}_{\text{GS}} = -4.5\text{V}, \text{I}_D = -350\text{mA}$
			0.7	1.05		$\text{V}_{\text{GS}} = -2.5\text{V}, \text{I}_D = -300\text{mA}$
			1.0	1.7		$\text{V}_{\text{GS}} = -1.8\text{V}, \text{I}_D = -150\text{mA}$
Forward Transfer Admittance	$ Y_{\text{fs} }$	-	0.9	-	S	$\text{V}_{\text{DS}} = -10\text{V}, \text{I}_D = -250\text{mA}$
Diode Forward Voltage (Note 4)	V_{SD}		-0.8	-1.2	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_S = -150\text{mA}$
DYNAMIC CHARACTERISTICS						
Input Capacitance	C_{iss}	-	59.76	-	pF	$\text{V}_{\text{DS}} = -16\text{V}, \text{V}_{\text{GS}} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	-	12.07	-	pF	
Reverse Transfer Capacitance	C_{rss}	-	6.36	-	pF	
Total Gate Charge	Q_g	-	622.4	-	pC	$\text{V}_{\text{GS}} = -4.5\text{V}, \text{V}_{\text{DS}} = -10\text{V}, \text{I}_D = -250\text{mA}$
Gate-Source Charge	Q_{gs}	-	100.3	-	pC	
Gate-Drain Charge	Q_{gd}	-	132.2	-	pC	
Turn-On Delay Time	$t_{\text{D}(\text{on})}$	-	5.1	-	ns	$\text{V}_{\text{DD}} = -10\text{V}, \text{V}_{\text{GS}} = -4.5\text{V}, R_L = 47\Omega, R_G = 10\Omega, \text{I}_D = -200\text{mA}$
Turn-On Rise Time	t_r	-	8.1	-	ns	
Turn-Off Delay Time	$t_{\text{D}(\text{off})}$	-	28.4	-	ns	
Turn-Off Fall Time	t_f	-	20.7	-	ns	

Notes: 4. Short duration pulse test used to minimize self-heating effect.



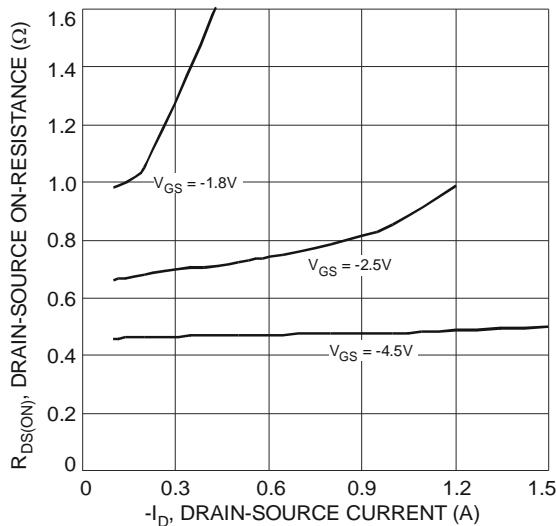


Fig. 3 Typical On-Resistance
vs. Drain Current and Gate Voltage

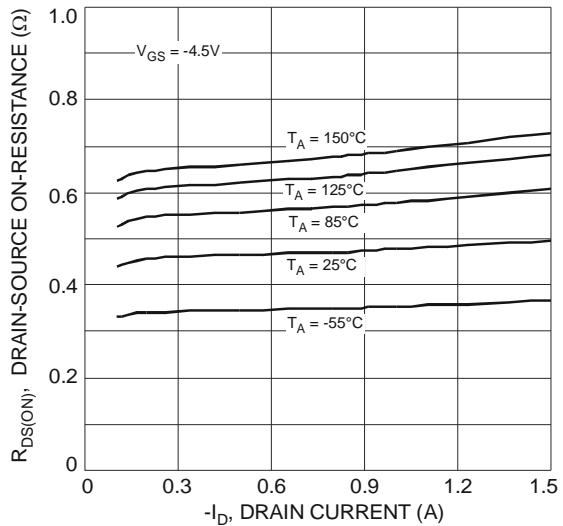


Fig. 4 Typical On-Resistance
vs. Drain Current and Temperature

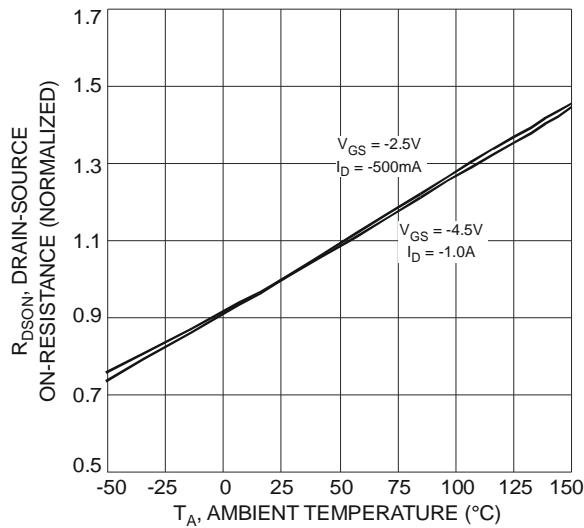


Fig. 5 On-Resistance Variation with Temperature

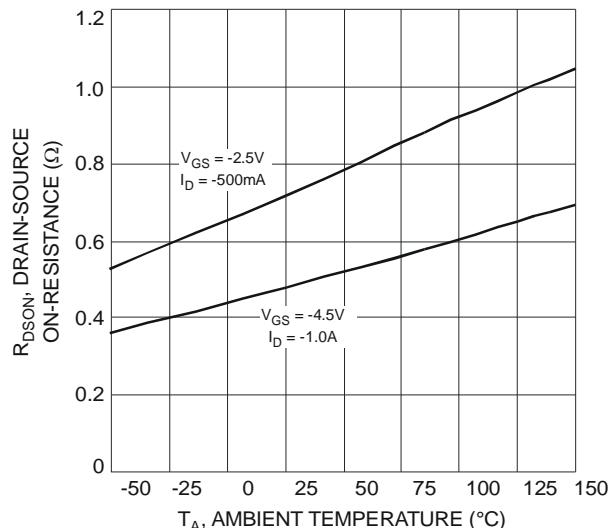


Fig. 6 On-Resistance Variation with Temperature

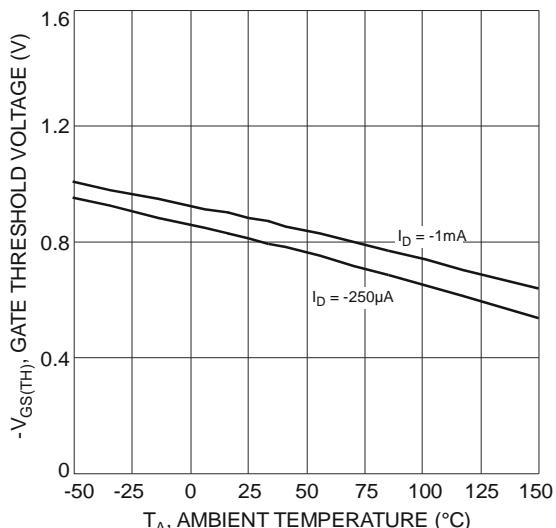


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

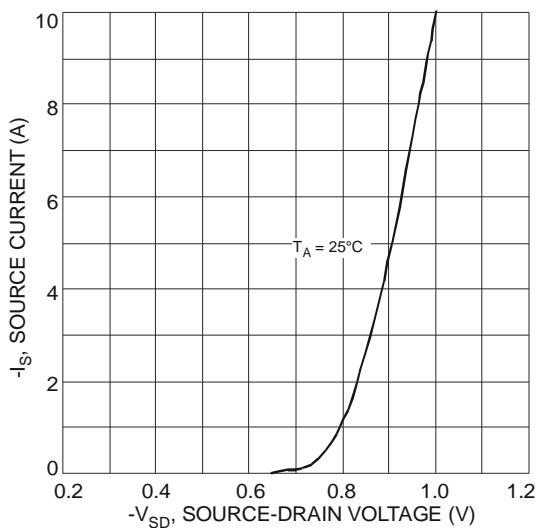
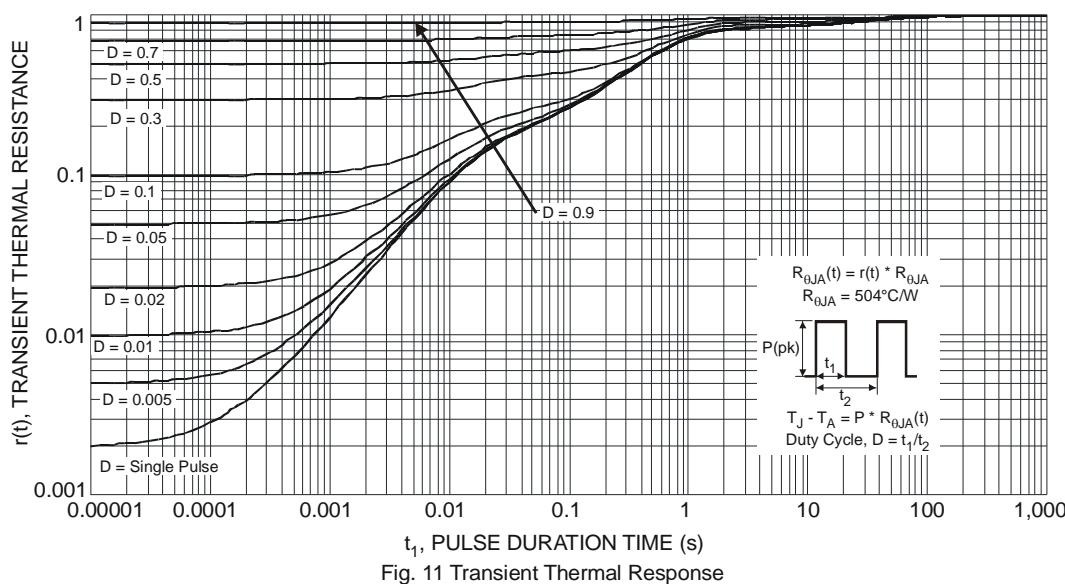
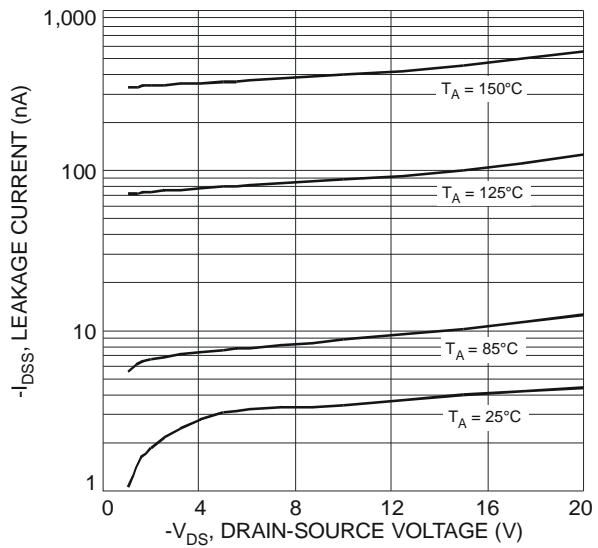
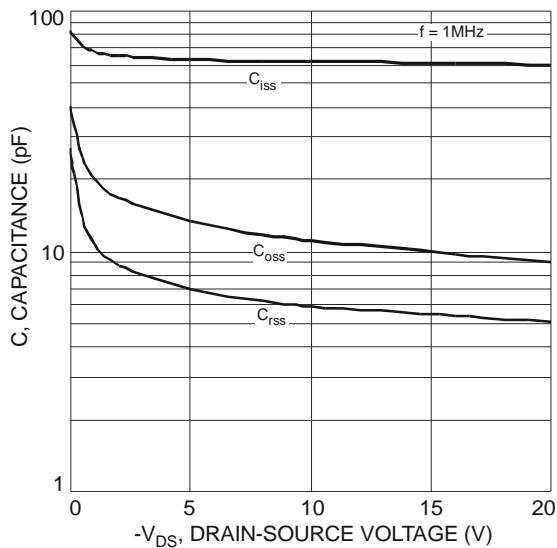


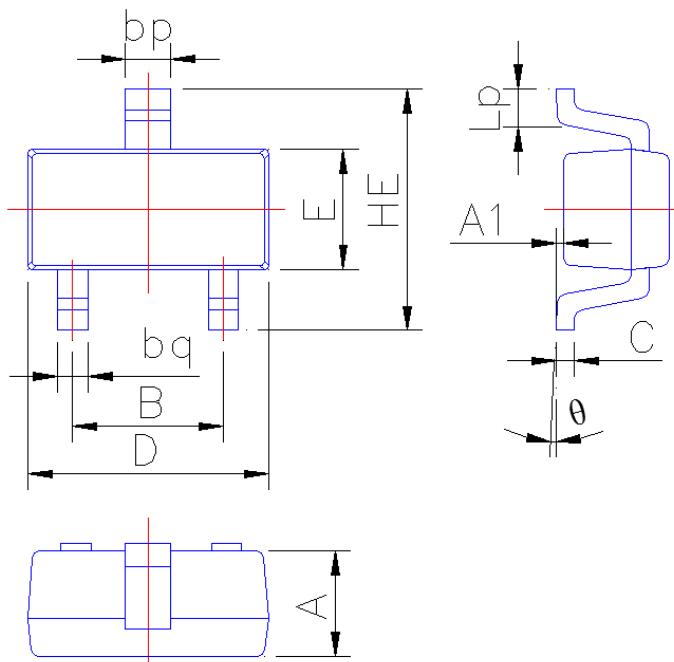
Fig. 8 Diode Forward Voltage vs. Current



PACKAGE OUTLINE

Plastic surface mounted package; 3 leads

SOT-523



Symbol	Dimension in Millimeters	
	Min	Max
A	0.60	0.80
A1	0.010	0.100
B	0.95	1.05
bp	0.26	0.40
bq	0.16	0.30
C	0.09	0.15
D	1.50	1.70
E	0.70	0.85
HE	1.45	1.75
Lp	0.16	0.36
θ	0°	5°